

Notice of References Cited	Application/Control No. 10/622,532	Applicant(s)/Patent Under Reexamination LEE, WON KWON	
	Examiner DuyVu n. Deo	Art Unit 1765	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,998,278	12-1999	Yu, Simon Yeou-Chong	438/424
	B	US-2003/0022458	01-2003	Koh, Chao-Ming	438/424
	C	US-6,277,707	08-2001	Lee et al.	438/430
	D	US-6,589,879	07-2003	Williams et al.	438/714
	E	US-2002/0155708	10-2002	Lo et al.	438/689
	F	US-6,461,937	10-2002	Kim et al.	438/431
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.